



Preliminary data

SPN01N60S5

Cool MOS Power-Transistor

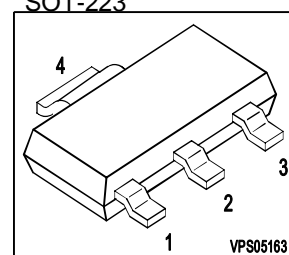
- New revolutionary high voltage technology
- Ultra low gate charge
- Extreme dv/dt rated
- Optimized capacitances
- Improved noise immunity



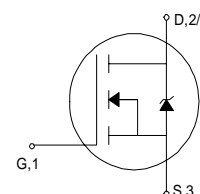
Product Summary

$V_{DS} @ T_{jmax}$	650	V
$R_{DS(on)}$	6	Ω
I_D	0.3	A

SOT-223



Type	Package	Ordering Code	Marking
SPN01N60S5	SOT-223	Q67040-S4208	01N60S5



Maximum Ratings, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Value	Unit
Continuous drain current	I_D		A
$T_A = 25\text{ }^\circ\text{C}$		0.3	
$T_A = 70\text{ }^\circ\text{C}$		0.2	
Pulsed drain current ¹⁾	$I_{D\text{ puls}}$	1.6	
$T_A = 25\text{ }^\circ\text{C}$			
Reverse diode dv/dt	dv/dt	6	kV/ μs
$I_S = 0.3\text{ A}$, $V_{DS} < V_{DSS}$, $di/dt = 100\text{ A}/\mu\text{s}$, $T_{jmax} = 150\text{ }^\circ\text{C}$			
Gate source voltage	V_{GS}	± 20	V
Power dissipation	P_{tot}	1.8	W
$T_A = 25\text{ }^\circ\text{C}$			
Operating and storage temperature	T_j, T_{stg}	-55... +150	$^\circ\text{C}$

**Electrical Characteristics**, at $T_j = 25\text{ °C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

Thermal Characteristics

Thermal resistance, junction - soldering point	R_{thJS}	-	35	-	K/W
SMD version, device on PCB:	R_{thJA}				K/W
@ min. footprint		-	110	-	
@ 6 cm ² cooling area ²⁾		-	-	72	

Static Characteristics, at $T_j = 25\text{ °C}$, unless otherwise specified

Drain-source breakdown voltage $V_{GS} = 0\text{ V}$, $I_D = 0.25\text{ mA}$	$V_{(BR)DSS}$	600	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 250\text{ }\mu\text{A}$, $T_j = 25\text{ °C}$	$V_{GS(th)}$	2.3	3	3.7	
Zero gate voltage drain current, $V_{DS} = V_{DSS}$ $V_{GS} = 0\text{ V}$, $T_j = 25\text{ °C}$ $V_{GS} = 0\text{ V}$, $T_j = 150\text{ °C}$	I_{DSS}	-	0.5	1	μA
Gate-source leakage current $V_{GS} = 20\text{ V}$, $V_{DS} = 0\text{ V}$	I_{GSS}	-	-	100	nA
Drain-source on-state resistance $V_{GS} = 10\text{ V}$, $I_D = 0.2\text{ A}$	$R_{DS(on)}$	-	5.5	6	Ω

¹current limited by T_{jmax} ² Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical without blown air.



Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Dynamic Characteristics

Transconductance	g_{fs}	$V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$, $I_D = 0.2\text{A}$	-	0.45	-	S
Input capacitance	C_{iss}	$V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1\text{MHz}$	-	100	-	pF
Output capacitance	C_{oss}		-	40	-	
Reverse transfer capacitance	C_{rss}		-	2.5	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 350\text{V}$, $V_{GS} = 10\text{V}$, $I_D = 0.3\text{A}$, $R_G = 100\Omega$	-	45	-	ns
Rise time	t_r		-	30	-	
Turn-off delay time	$t_{d(off)}$		-	60	90	
Fall time	t_f		-	30	45	

Gate Charge Characteristics

Gate to source charge	Q_{gs}	$V_{DD} = 350\text{V}$, $I_D = 0.3\text{A}$	-	0.9	-	nC
Gate to drain charge	Q_{gd}		-	2.2	-	
Total gate charge	Q_g	$V_{DD} = 350\text{V}$, $I_D = 0.3\text{A}$, $V_{GS} = 0$ to 10V	-	3.9	5	

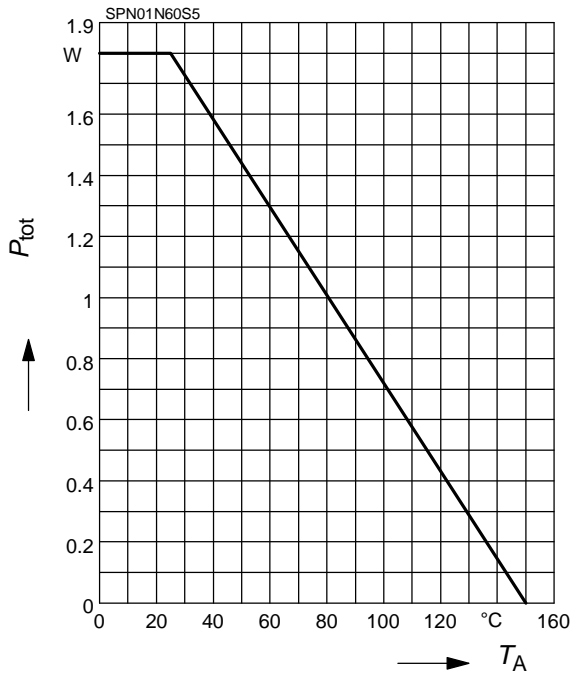
Reverse Diode

Inverse diode continuous forward current	I_S	$T_C = 25\text{ }^\circ\text{C}$	-	-	0.3	A
Inverse diode direct current, pulsed	I_{SM}		-	-	1.6	
Inverse diode forward voltage	V_{SD}	$V_{GS} = 0\text{V}$, $I_F = 0.3\text{A}$	-	0.85	1.05	V
Reverse recovery time	t_{rr}	$V_R = 100\text{V}$, $I_F = I_S$, $di_F/dt = 100\text{A}/\mu\text{s}$	-	200	340	ns
Reverse recovery charge	Q_{rr}		-	0.45	-	



Power Dissipation

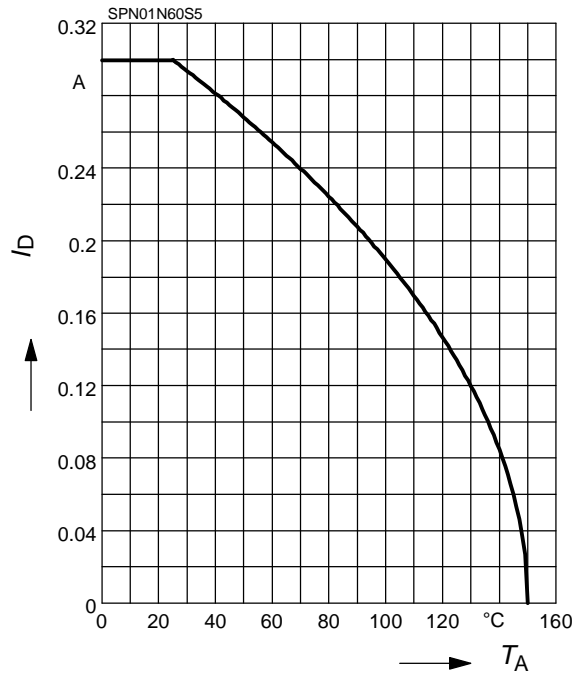
$P_{tot} = f(T_A)$



Drain current

$I_D = f(T_A)$

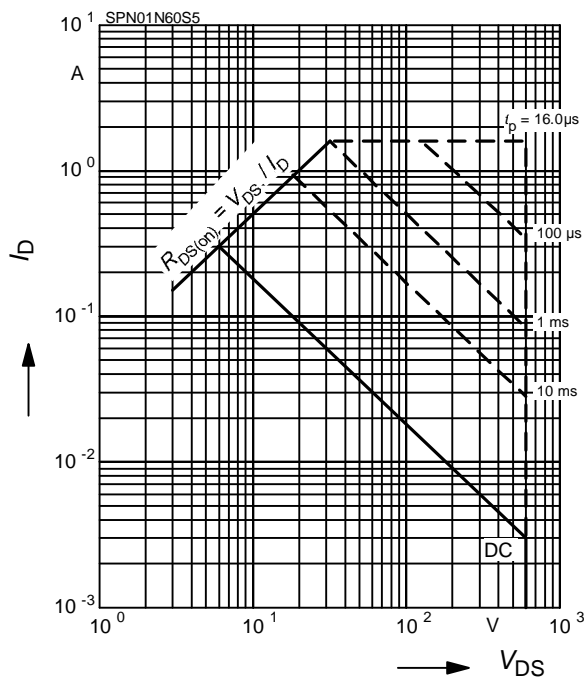
parameter: $V_{GS} \geq 10\text{ V}$



Safe operating area

$I_D = f(V_{DS})$

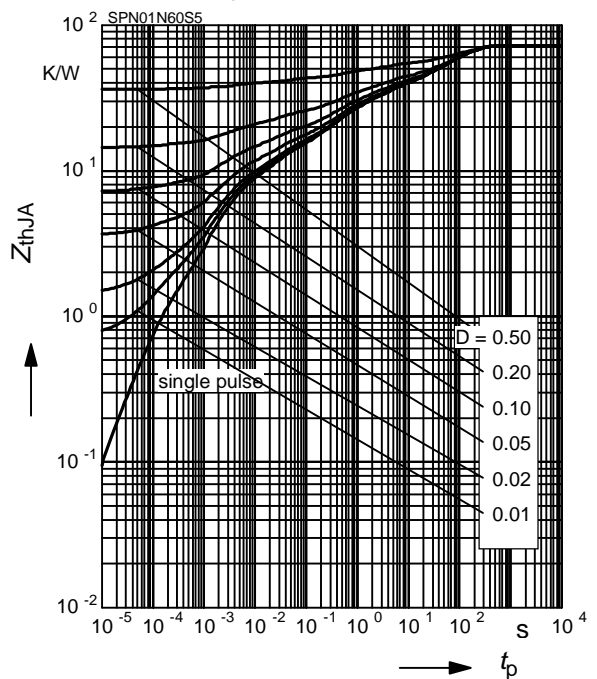
parameter: $D=0.01, T_C=25^\circ\text{C}$



Transient thermal impedance

$Z_{thJA} = f(t_p)$

parameter: $D = t_p/T$

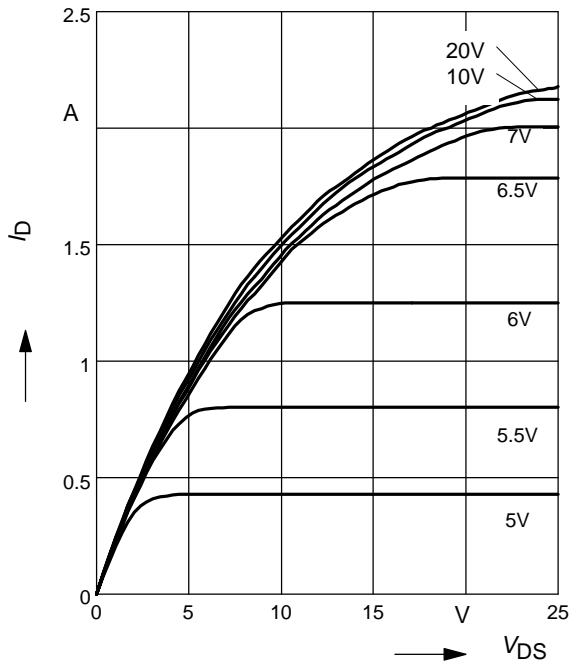




Typ. output characteristic

$I_D = f(V_{DS})$

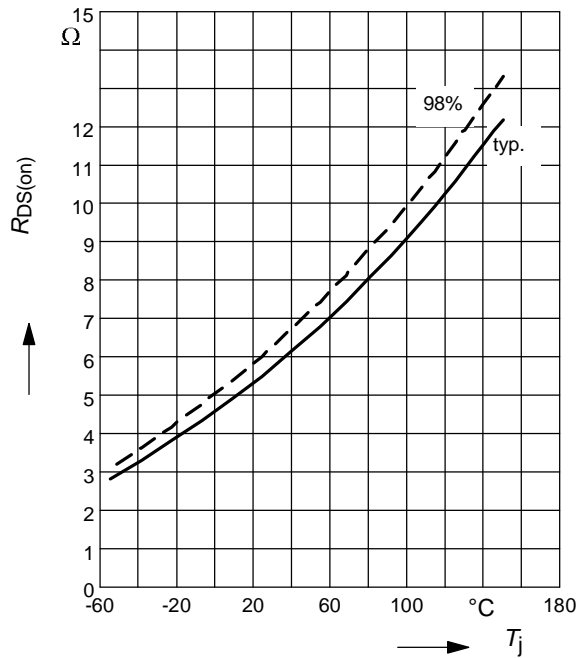
Parameter: $V_{GS}, T_j = 25\text{ }^\circ\text{C}$



Drain-source on-resistance

$R_{DS(on)} = f(T_j)$

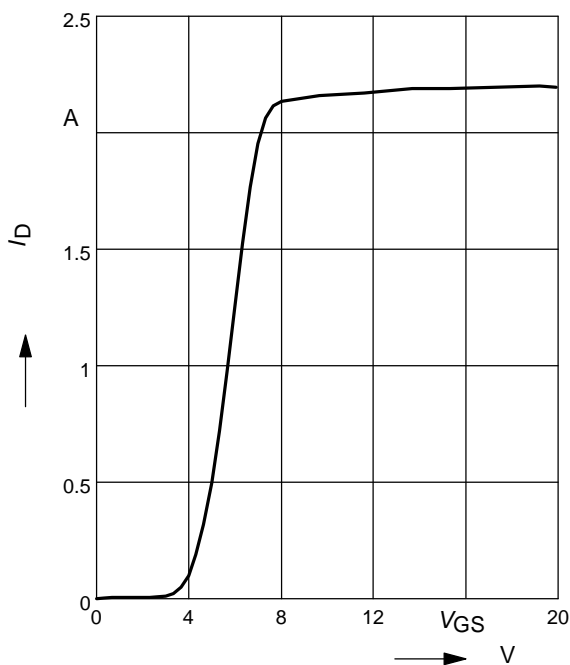
parameter : $I_D = 0.2\text{ A}, V_{GS} = 10\text{ V}$



Typ. transfer characteristics

$I_D = f(V_{GS})$

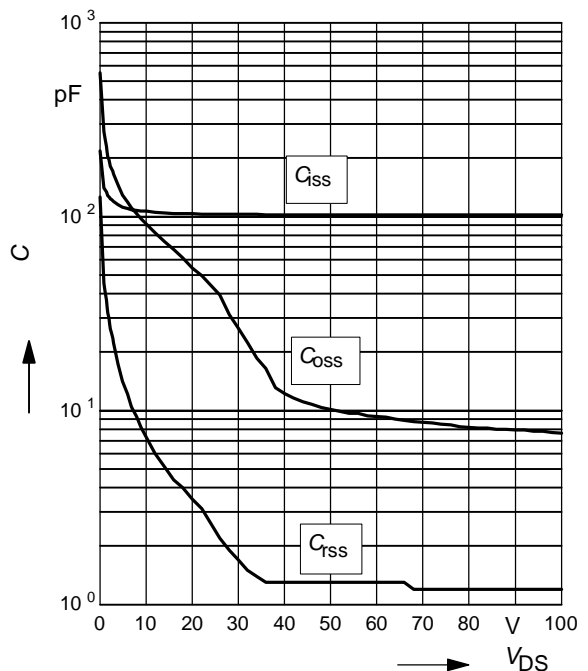
$V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$



Typ. capacitances

$C = f(V_{DS})$

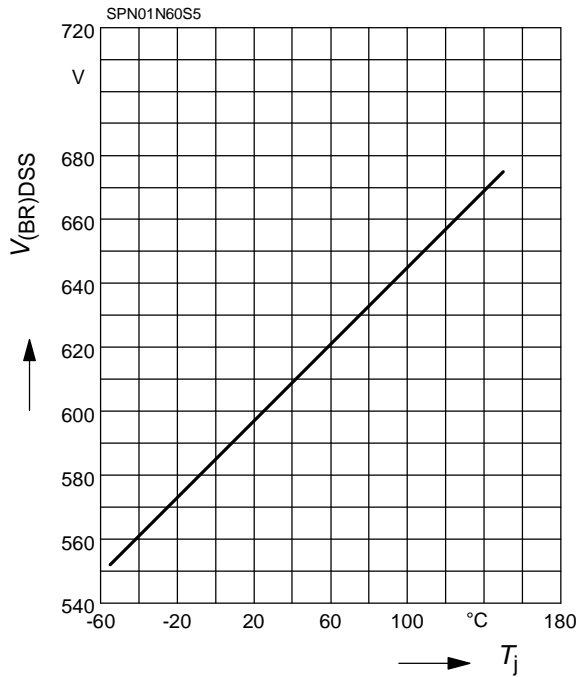
parameter: $V_{GS} = 0\text{ V}, f = 1\text{ MHz}$





Drain-source breakdown voltage

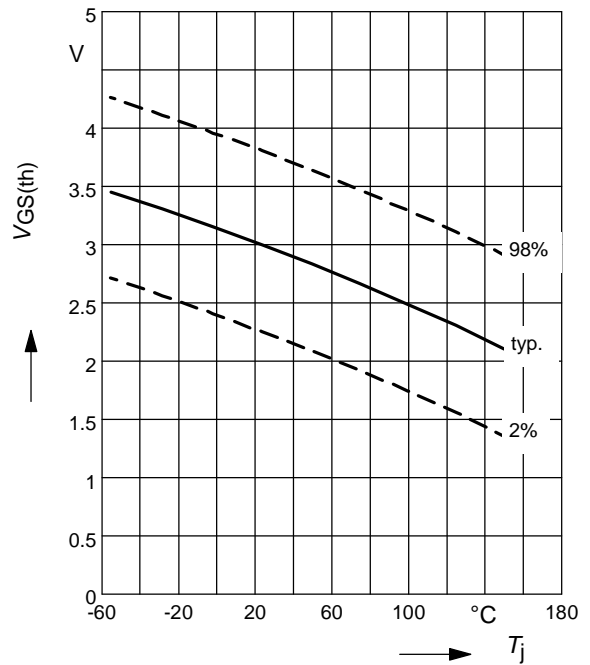
$$V_{(BR)DSS} = f(T_j)$$



Gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

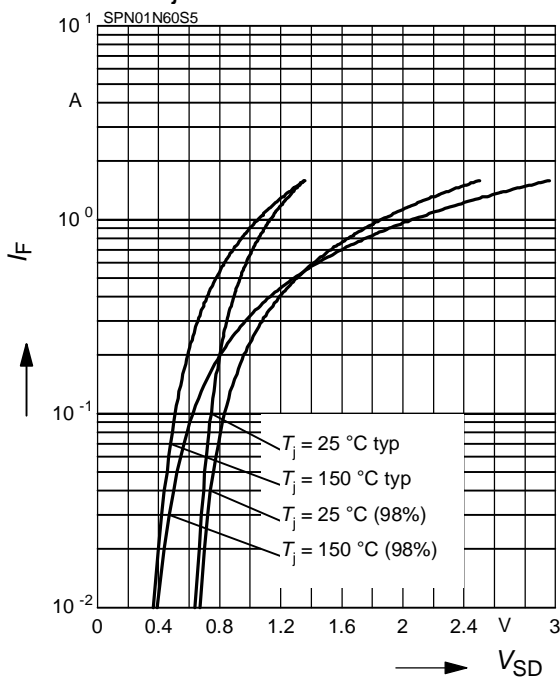
parameter: $V_{GS} = V_{DS}$, $I_D = 250 \mu A$



Forward characteristics of reverse diode

$$I_F = f(V_{SD})$$

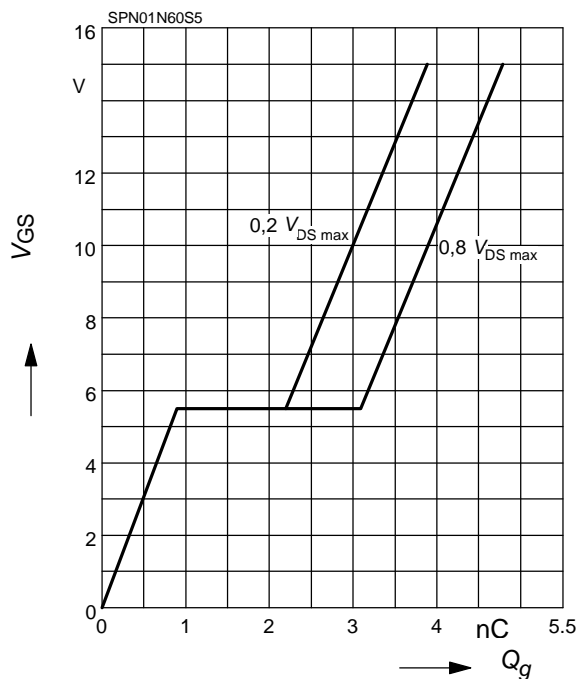
parameter: T_j , $t_p = 10 \mu s$

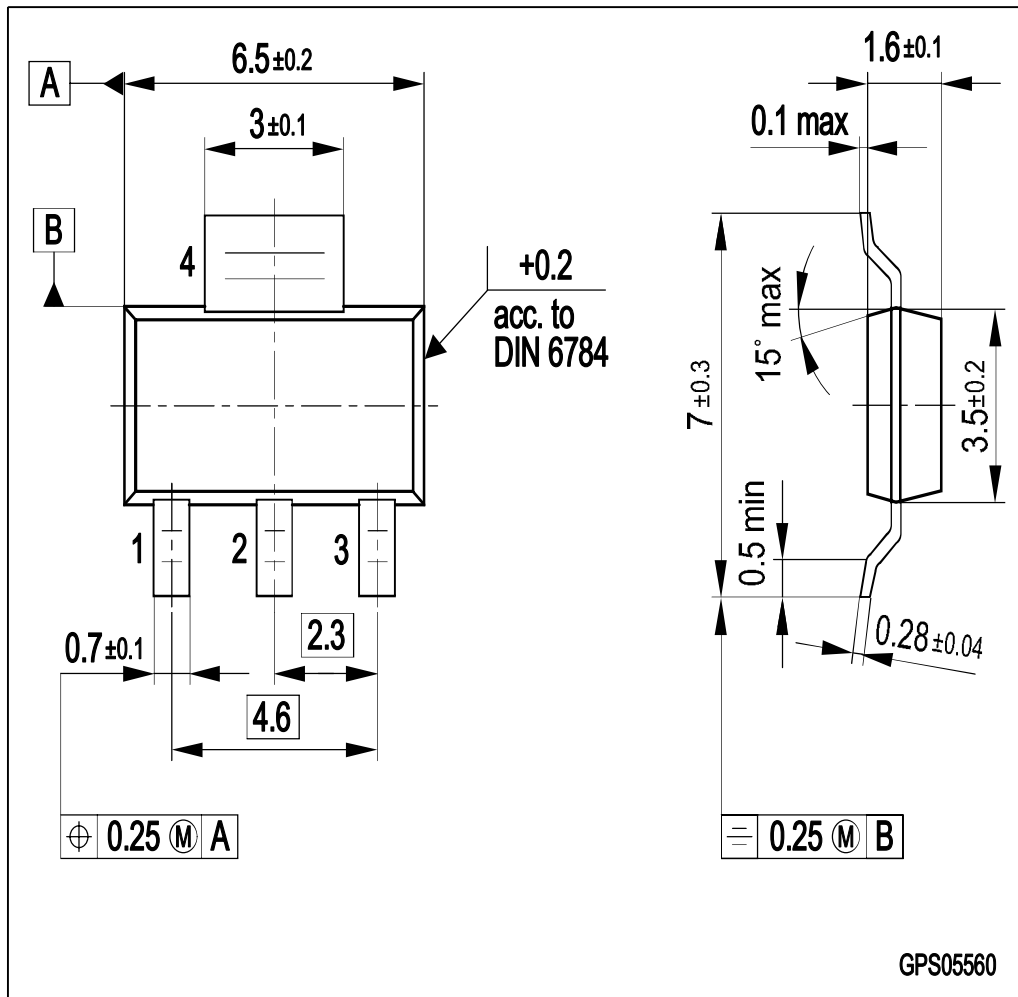


Typ. gate charge

$$V_{GS} = f(Q_{Gate})$$

parameter: $I_D = 0.3 A$ pulsed







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